



Test Report No.: NK-12-R-181

FCC and IC Certification

Nemko Korea Co., Ltd.

155 & 159, Osan-Ro, Mohyeon-Myeon, Cheoin-Gu, Yongin-Si, Gyeonggi-Do, 449-852 KOREA, REPUBLIC OF

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FCC and IC EVALUATION REPORT FOR CERTIFICATION

Applicant :

Samsung Electronics Co., Ltd.

129, Samsung-ro, Yeongtong-gu,

Suwon-si, Gyeonggi-do, Korea

(Post code : 443-742)

Attn. : Mr. Jaywoo. Lee

Dates of Issue : October 29, 2012

Test Report No. : NK-12-R-181

Test Site : Nemko Korea Co., Ltd.

**FCC ID
IC ID**

**A3LSSG5100
649E-SSG5100**

Brand Name

SAMSUNG

Contact Person

**Samsung Electronics Co., Ltd.
129, Samsung-ro, Yeongtong-gu,
Suwon-si, Gyeonggi-do, Korea 443-742
Mr. Jaywoo. Lee
Telephone No. : +82-31-277-2569**

Applied Standard:

FCC 47 CFR Part 15C and IC RSS-210

Classification:

FCC Part 15 Spread Spectrum Transmitter (DSS)

EUT Type:

3D Active Glasses

The device bearing the brand name and model specified above has been shown to comply with the applicable technical standards as indicated in the measurement report and was tested in accordance with the measurement procedures specified in ANSI C63.4-2003, ANSI C63.10. The client should not use it to claim product endorsement by TAF or any government agencies. The test results in the report only apply to the tested sample.

I attest to the accuracy of data and all measurements reported herein were performed by me or were made under my supervision and are correct to the best of my knowledge and belief. I assume full responsibility for the completeness of these measurements and vouch for the qualifications of all persons taking them.

**Tested By : Jin-Ha, Ko
Engineer**

Oct. 29, 2012

Oct. 29, 2012

**Reviewed By : Deokha Ryu
Manager & Chief Engineer**

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1. SCOPE

Measurement and determination of electromagnetic emissions (EME) of radio frequency devices including intentional and/or unintentional radiators for compliance with the technical rules and regulations of the Federal Communications Commission under FCC part 15 and IC RSS-210.

Responsible Party :	Samsung Electronics Co., Ltd.
Contact Person :	Mr. Jaywoo. Lee
Manufacturer :	Samsung Electronics Co., Ltd. 129, Samsung-ro, Yeongtong-gu, Suwon-si, Gyeonggi-do, Korea 443-742

- FCC ID: A3LSSG5100
- IC: 649E-SSG5100
- Model: SSG-5100GB
- Brand Name: SAMSUNG
- EUT Type: 3D Active Glasses
- Classification: 15C Intentional Radiator
- Applied Standard: FCC 47 CFR Part 15 subpart C and IC RSS-210
- Test Procedure(s): ANSI C63.4-2003, ANSI C63.10 and FCC Public Notice DA 00-705 dated March 30, 2000 entitled "Filling and Measurement Guidelines for Frequency Hopping Spread Spectrum Systems"
- Dates of Test: October 10, 2012 ~ October 24, 2012
- Place of Tests: Nemko Korea Co., Ltd.

2. INTRODUCTION

2.1 Test facility

The measurement procedure described in American National Standard for Methods of Measurement of Radio-Noise Emissions from Low-Voltage Electrical and Electronic Equipment in the Range of 9 kHz to 40 GHz (ANSI C63.4-2003) , the American National Standard for Testing Unlicensed Wireless Devices (ANSI C63.10-2009) were used in determining radiated and conducted emissions emanating from **Samsung Electronics Co., Ltd. FCC ID : A3LSSG5100** and **IC ID : 649E-SSG5100**

These measurement tests were conducted at **Nemko Korea Co., Ltd. EMC Laboratory**.

The site address is 155 & 159, Osan-Ro, Mohyeon-Myeon, Cheoin-Gu, Yongin-Si, Gyeonggi-Do, 449-852 KOREA, REPUBLIC OF.

The area of Nemko Korea Corporation Ltd. EMC Test Site is located in a mountain area at 80 kilo-meters (48 miles) southeast and Incheon International Airport (Incheon Airport), 30 kilometers (18 miles) south-southeast from central Seoul.

It is located in the valley surrounded by mountains in all directions where ambient radio signal conditions are quiet and a favorable area to measure the radio frequency interference on open field test site for the computing and ISM devices manufactures.

The detailed description of the measurement facility was found to be in compliance with the requirements of § 2.948 according to ANSI C63.4 2003.



Nemko Korea Co., Ltd.
EMC Lab.

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Cheoin-Gu, Yongin-Si,
Gyeonggi-Do, 449-852 KOREA,
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Fig. 1. The map above shows the Seoul in Korea vicinity area.

The map also shows Nemko Korea Corporation Ltd. EMC Lab. and Incheon Airport.

2.2 Accreditation and listing

Accreditation type		Accreditation number
	FCC part 15/18 Filing site	Registration No. 97992
	CAB Accreditation for DOC	Designation No. KR0026
	KOLAS Accredited Lab. (Korea Laboratory Accreditation Scheme)	Registration No. 155
	Canada IC Registered site	Site No. 2040E
	VCCI registration site(RE/CE/Telecom CE)	Member No. 2118
	EMC CBTL	-
	KCC(RRL)Designated Lab.	Registration No. KR0026
	SASO registered Lab and Certification Body	Registration No. 2008-15

3. TEST CONDITIONS & EUT INFORMATION

3.1 Operation During Test

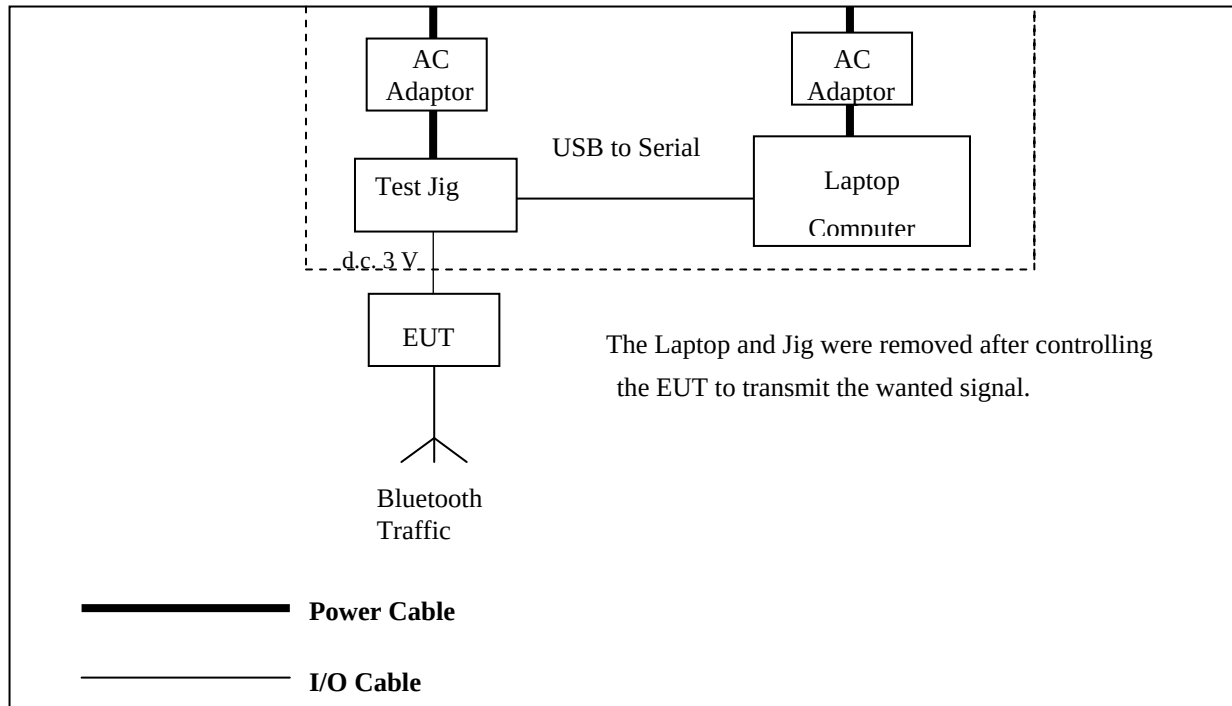
The Laptop and Test Jig were used to control the EUT to transmit the wanted TX channel by the Bluetool testing program which manufacturer supported. The Laptop was removed after controlling the EUT to transmit the wanted signal. The EUT was measured at X, Y, Z-Axis in Bluetooth Traffic mode with the maximum output power in accordance with the manufacturer's specifications. The worst data were recorded in the report.

Test frequency		2402 MHz	2441 MHz	2480 MHz
GFSK	Power setting	0 dBm	0 dBm	0 dBm
	Packet type	DH5	DH5	DH5

3.2 Support Equipment

EUT	Samsung Electronics Co., Ltd. Model: SSG-5100GB FCC ID : A3LSSG5100	S/N: N/A
Laptop Computer	Samsung Electronics Co., Ltd. Model : NT-R520 1.2 m UART to USB shielded cable	FCC DOC S/N: ZK6V93FS800012Y
AC/DC Adaptor	Chicony Power Technology Co., Ltd. Model : AD-6019R 1.0 m unshielded power cable	FCC DOC S/N: CNBA440024ADON897I2602

3.3 Setup Drawing



3.4 EUT Information

The EUT is the **Samsung 3D Active Glasses FCC ID: A3LSSG5100, IC ID: 649E-SSG5100.**

Specifications:

EUT Type	3D Active Glasses
Model Name	SSG-5100GB
Brand Name	SAMSUNG
RF Frequency	2402 MHz ~ 2480 MHz
Peak Power Output (Conducted)	-1.77 dBm
FCC Classification	FCC Part 15 Spread Spectrum Transmitter (DSS)
Method/System	Frequency Hopping Spread Spectrum (FHSS)
Channel Number	79
Modulation	GFSK
Antenna Gain (Peak)	3.96 dBi
Power	3.0 Vdc (Lithium Battery)
Size	137 mm x 160 mm x 40 mm
Weight	25 g (Including the Battery)

4. SUMMARY OF TEST RESULTS

The EUT has been tested according to the following specification:

Name of Test	FCC Paragraph No.	IC Paragraph No.	Result	Remark
Conducted Emission	15.207	RSS-GEN 7.2.4	N/A	
Radiated Emission	15.209	RSS-210 A8.5	Complies	
20dB Bandwidth and	15.247(a)(1)(iii)	RSS-210 A8.1	Complies	
Carrier Frequency Separation	15.247(a)(1)	RSS-210 A8.1(2)	Complies	
Transmitter Average Time of Occupancy	15.247(a)(1)(iii)	RSS-210 A8.1(4)	Complies	
Peak Power Output	15.247(b)(1)	RSS-210 A8.4(2)	Complies	
Conducted Spurious Emission	15.247(d)	RSS-210 A8.5	Complies	
Radiated Spurious Emission	15.247(d)	RSS-210 A8.5	Complies	
Number of Hopping channels	15.247(a)(1)(iii)	RSS-210 A8.1(4)	Complies	

5. RECOMMENDATION/CONCLUSION

The data collected shows that the **Samsung 3D Active Glasses FCC ID: A3LSSG5100, IC ID: 649E-SSG5100** is in compliance with Part 15 Subpart C 15.247 of the FCC Rules.

6. ANTENNA REQUIREMENTS

§15.203 of the FCC Rules part 15 Subpart C

: An intentional radiator shall be designed to ensure that no antenna other than that furnished by the responsible party shall be used with the device. The use of a permanently attached antenna or of an antenna that uses a unique coupling to the intentional radiator shall be considered sufficient to comply with the provisions of this section.

The antenna of the **Samsung 3D Active Glasses FCC ID: A3LSSG5100, IC ID: 649E-SSG5100** is **permanently attached** and there are no provisions for connection to an external antenna. It complies with the requirement of §15.203.

7. DESCRIPTION OF TESTS

7.1 Conducted Emissions

The Line conducted emission test facility is located inside a 4 x 7 x 2.5 meter shielded enclosure.

It is manufactured by EM engineering. The shielding effectiveness of the shielded room is in accordance with MIL-STD-285 or NSA 65-6.

A 1 m x 1.5 m wooden table 0.8 m height is placed 0.4 m away from the vertical wall and 1.5 m away from the side of wall of the shielded room Rohde & Schwarz (ESH3-Z5) and (ESH2-Z5) of the 50 ohm/50 uH Line Impedance Stabilization Network(LISN) are bonded to the shielded room. The EUT is powered from the Rohde & Schwarz LISN (ESH3-Z5) and the support equipment is powered from the Rohde & Schwarz LISN (ESH2-Z5). Power to the LISNs are filtered by high-current high insertion loss Power line filters. The purpose of filter is to attenuate ambient signal interference and this filter is also bonded to shielded enclosure. All electrical cables are shielded by tinned copper zipper tubing with inner diameter of 1 / 2 ".

If DC power device, power will be derived from the source power supply it normally will be powered from and this supply lines will be connected to the LISNs,

All interconnecting cables more than 1 meter were shortened by non-inductive bundling (serpentine fashion) to a 1 meter length.

Sufficient time for EUT, support equipment, and test equipment was allowed in order for them to warm up to their normal operating condition. The RF output of the LISN was connected to the spectrum analyzer to determine the frequency producing the maximum EME from the EUT.

The spectrum was scanned from 150 kHz to 30 MHz with 200 msec sweep time.

The frequency producing the maximum level was re-examined using the EMI test receiver. (Rohde & Schwarz ESCS30).

The detector functions were set to CISPR quasi-peak mode & average mode.

The bandwidth of receiver was set to 9 kHz. The EUT, support equipment, and interconnecting cables were arranged and manipulated to maximize each EME emission.

Each emission was maximized by; switching power lines; varying the mode of operation or resolution; clock or data exchange speed; scrolling H pattern to the EUT and of support equipment, and powering the monitor from the floor mounted outlet box and computer aux AC outlet, if applicable; whichever determined the worst case emission.

Each EME reported was calibrated using the R&S signal generator.

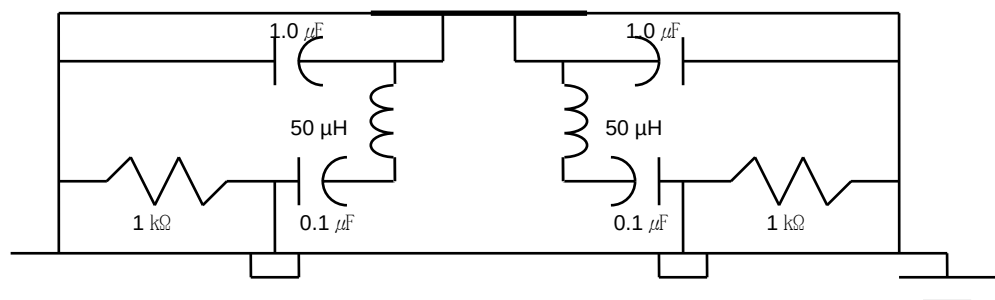


Fig. 2. LISN Schematic Diagram

7.2 Radiated Emissions

Measurement were made at 10 meter Semi-Anechoic Chamber using broad band antennas, broadband amplifier, and spectrum analyzer to determine the frequency producing the maximum EME. Appropriate precaution was taken to ensure that all EME from the EUT were maximized and investigated. The Technology configuration, clock speed, mode of operation or video resolution, turntable azimuth with respect to the antenna was note for each frequency found.

The test receiver was scanned from 9 kHz to 30 MHz using Loop Antenne(Rohde&Schwarz, HFH2-Z2) and 30 MHz to 1000 MHz using TRILOG Broadband Test Antenna (Schwarzbeck, VULB 9163) in semi anechoic chamber. Above 1 GHz, Horn antenna (Scwarzbeck BBHA 9120D: up to 18 GHz, Q-par Angus QSH20S20 : 18 to 26.5 GHz, QSH22K20: up to 40 GHz) was used.

The test equipment was placed on a wooden table.

Sufficient time for the EUT, support equipment, and test equipment was allowed in order for them to warm up to their normal operating condition.

Each frequency found during measurements was reexamined and investigated using EMI test receiver. (ESU 40 & FSP 40)

The detector function were set to CISPR quasi-peak mode and the bandwidth of the receiver were set to 120 kHz or 1 MHz depending on the frequency or type of signal.

The half wave dipole antenna was tuned to the frequency found during preliminary radiated measurements.

The EUT support equipment and interconnecting cables were re configured to the setup producing the maximum emission for the frequency and were placed on top of a 0.8 m high non- metallic 1.0 x 1.5 meter table.

The EUT, support equipment and interconnecting cables were re-arranged and manipulated to maximize each EME emission.

The turn table containing the Technology was rotated; the antenna height was varied 1 to 4 meter and stopped at the azimuth or height producing the maximum emission. Each emission was maximized by : switching power lines; varying the mode of operation or resolution; clock or data exchange speed; scrolling H pattern to the EUT and of support equipment, and powering the monitor from the floor mounted outlet box and computer aux a.c. outlet, if applicable; whichever determined the worst case emission.

Each EME reported was calibrated using the R/S signal generator.

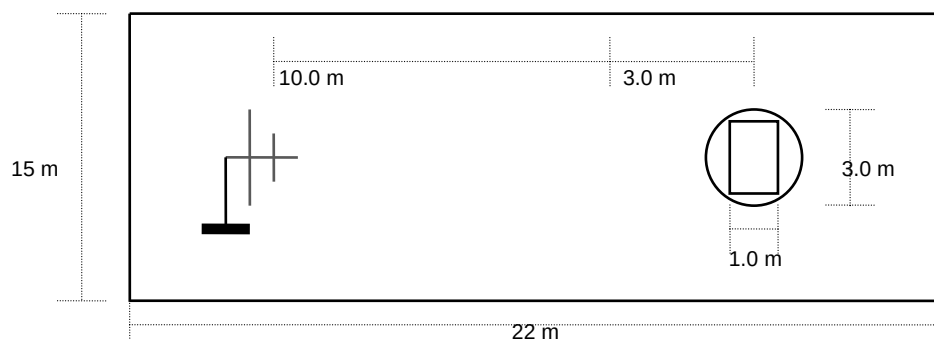
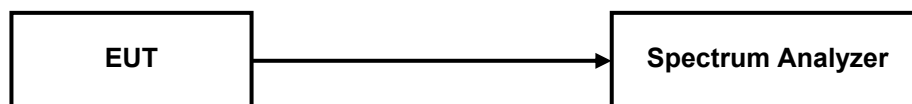


Fig. 3. Dimensions of semi anechoic chamber

7.3 20 dB Bandwidth and Carrier Frequency Separation

Test Setup



Test Procedure

The transmitter is set to the Low, Middle, High channels is connected to the spectrum analyzer.

Span = approximately 2 to 3 times the 20 dB bandwidth, centered on a hopping channel

RBW $\geq$ 1% of the 20 dB bandwidth

VBW $\geq$ RBW

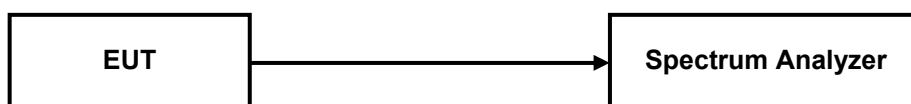
Sweep = auto

Detector function = peak

Trace = max hold

7.4 Transmitter Average Time of Occupancy

Test Setup



Test Procedure

The transmitter output is connected to a spectrum analyzer. The following spectrum analyzer setting is used.

Span = Zero span, centered on a hopping channel

RBW = 1 MHz, VBW $\geq$ RBW

Sweep = as necessary to capture the entire dwell time per hopping channel

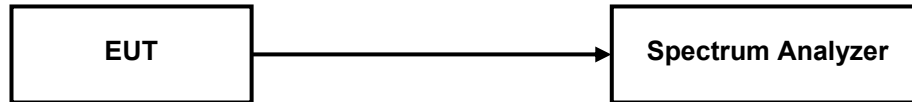
Detector function = Peak

Trace = Single sweep

Use the marker-delta function to determine the width of pulse

7.5 Number of Hopping Channels

Test Setup



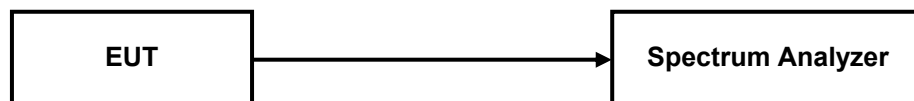
Test Procedure

The transmitter output is connected to a spectrum analyzer. The span is set to cover the entire authorized band, In either a single sweep or in multiple continuous sweeps. The RBW is set to 1 % of the span.

The spectrum analyzer is set to Max Hold.

7.6 Maximum Peak Output Power

Test Setup

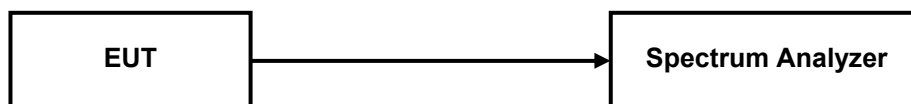


Test Procedure

The transmitter is set to the Low, Middle, High channels is connected to the spectrum analyzer. The RBW of spectrum analyzer is set to 3 MHz and VBW is set to the 3 MHz. The sweep time is coupled.

7.7 Conducted Spurious Emission

Test Setup



Test Procedure

The transmitter is connected to the spectrum analyzer.

The RBW of spectrum analyzer is set to 100 kHz and VBW is set to the 300 kHz.

Measurements are made over the 30 MHz to 25 GHz range with the transmitter set to the Lowest, middle and highest channels.

8. TEST DATA

8.1 Radiated Emissions

FCC §15.209, IC RSS-210 A8.5

Frequency (MHz)	Reading (dBμV/m)	Pol* (H/V)	Antenna Height (cm)	Turntable Angles (°)	AF+CL+Amp (dB)**	Result (dBμV/m)	Limit (dBμV/m)	Margin (dB)
319.06	38.4	V	100	315	-20.2	18.2	46.0	27.8
384.00	39.8	H	100	111	-18.2	21.6	46.0	24.4
432.01	40.6	H	100	133	-16.7	23.9	46.0	22.1
480.03	39.5	H	180	112	-15.8	23.7	46.0	22.3
528.05	35.9	H	180	309	-14.4	21.5	46.0	24.5
938.26	32.5	H	380	36	-9.7	22.8	46.0	23.2

Radiated Measurements at 3 meters

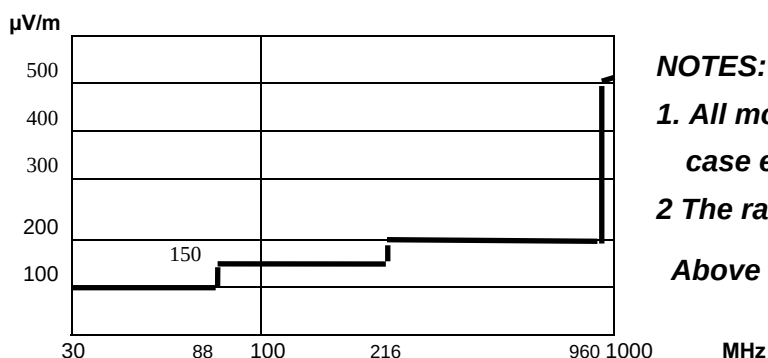


Fig. 4. Limits at 3 meters

NOTES:

1. All modes were measured and the worst-case emission was reported.

2 The radiated limits are shown on Figure 4.

Above 1 GHz the limit is 500 μV/m.

NOTES:

- *Pol. H = Horizontal V = Vertical
- **AF + CL + Amp. = Antenna Factor + Cable Loss + Amplifier.
- Measurements using CISPR quasi-peak mode below 1 GHz.
- The radiated emissions testing were made by rotating through three orthogonal axes.
The worst date was recorded.
- The limit is on the FCC Part section 15.209(a).

TEST DATA

8.2 20 dB Modulated Bandwidth

FCC §15.247(a)(1)(iii), RSS-210 A8.1

Test mode : Set to Lowest channel, Middle channel and Highest channel

Result:

Modulation Mode	Frequency(MHz)	Result(kHz)	Limit(kHz)
GFSK	2402	973.2	Non specified
GFSK	2441	970.6	Non specified
GFSK	2480	916.0	Non specified

PLOTS OF EMISSIONS

20 dB Bandwidth, Lowest Channel (2402 MHz)

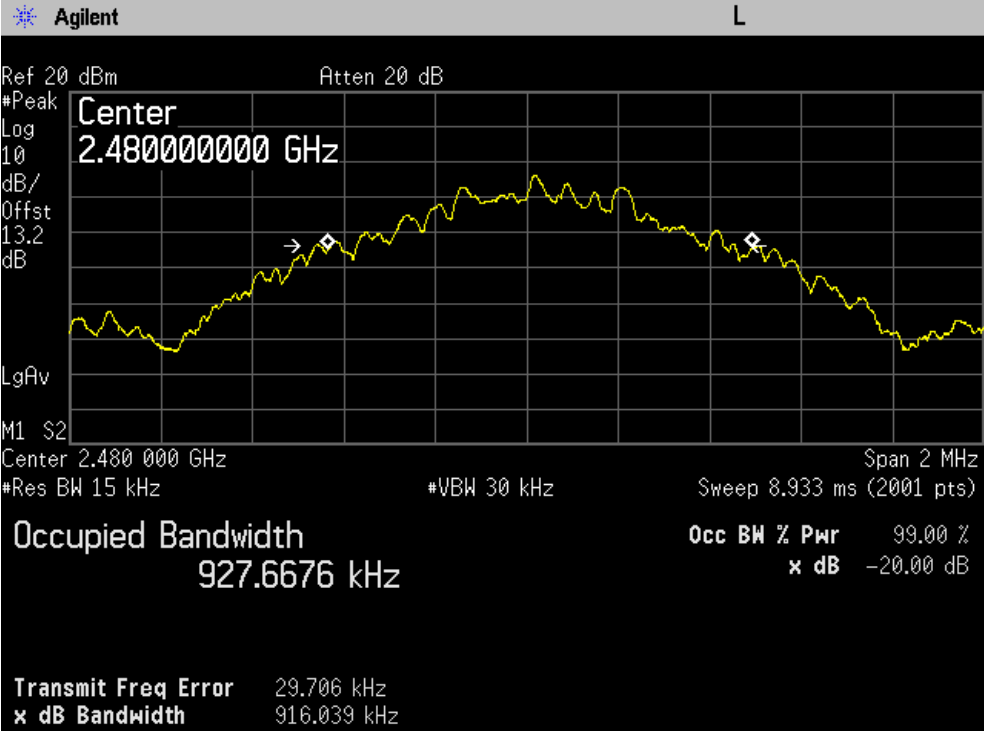


20 dB Bandwidth, Middle Channel (2441 MHz)



PLOTS OF EMISSIONS

20 dB Bandwidth, Highest Channel (2480 MHz)



TEST DATA

8.3 Carrier Frequency Separation

FCC §15.247(a)(1), RSS-210 A8.1(2)

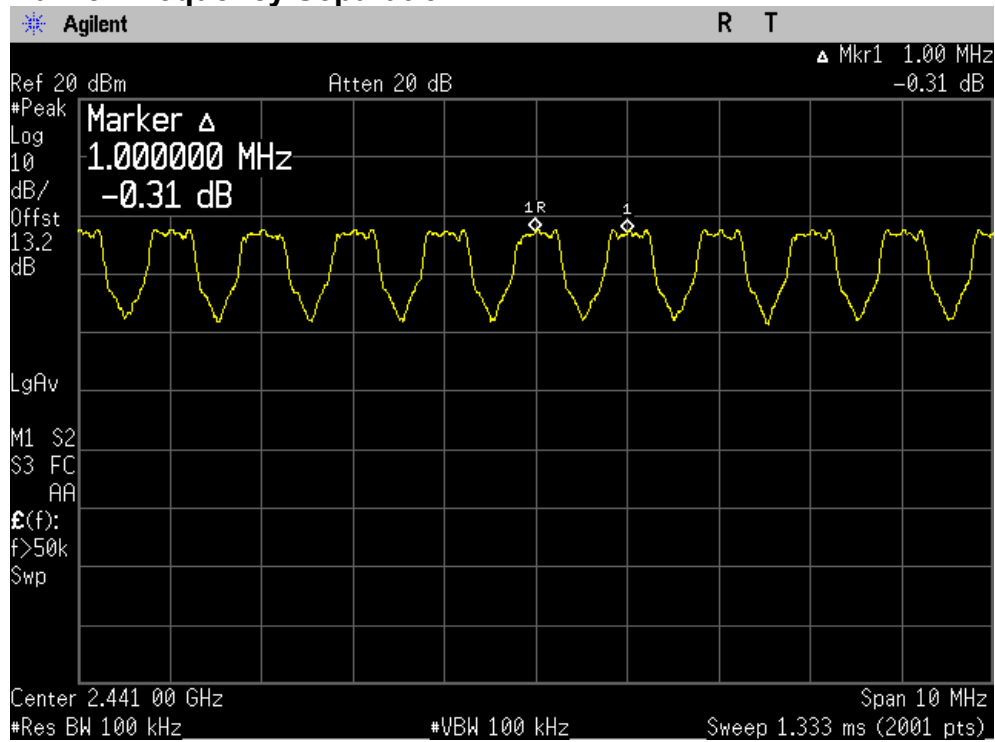
Test mode : Set to Hopping mode

Result:

Modulation Mode	Carrier Frequency Separation (kHz)	Limit (2 / 3 of 20dB Bandwidth) (kHz)	Margin (kHz)
GFSK	1000	648.8	351.2

PLOTS OF EMISSIONS

Carrier Frequency Separation



TEST DATA

8.4 Transmitter Average Time of Occupancy

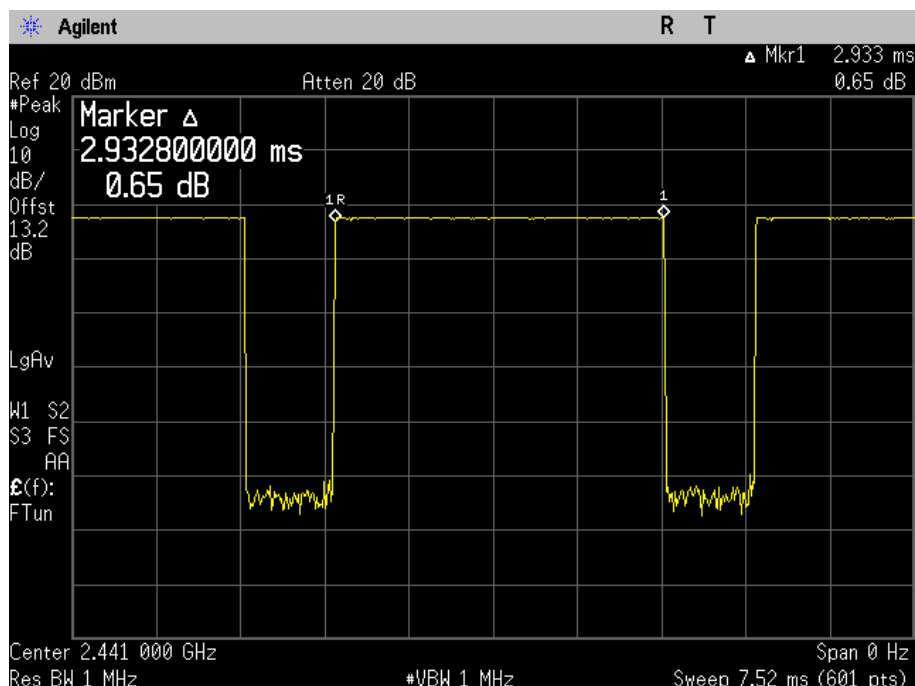
FCC §15.247(a)(1)(iii), RSS-210 A8.1(4)

Test mode : Set to Hopping mode

Result:

The average time of occupancy in the specified 31.6 second period (79 channels x 0.4 s) is equal to pulse width x (1600 / 6) / 79 x 31.6 second.

Pulse width (ms)	^{*)} Numbers of slots in 31.6 sec	^{**) Average time of Occupancy(ms)}	Limit (ms)	Margin (ms)
2.93	106.7	312.63	≤ 400	87.37



Notes:

The result was measured at DH5 mode in GFSK modulation, which has longest time in one transmission burst.

^{*)}Numbers of slots in 31.6 sec = (1600 / 6) / 79 x 31.6

^{**) Average time of Occupancy = pulse width x Numbers of slots in 31.6 sec}

TEST DATA

8.5 Number of Hopping Channels

FCC §15.247(a)(1)(iii), RSS-210 A8.1(4)

Test mode : Set to Hopping mode

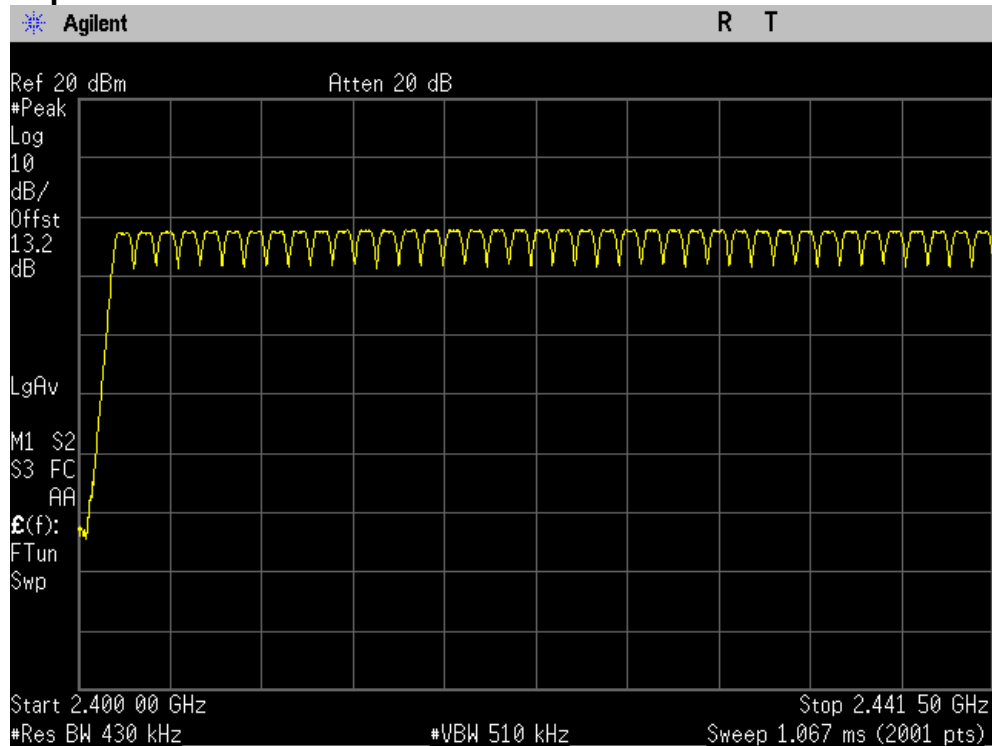
Result:

Total Hopping Channels = 40 + 39 = 79

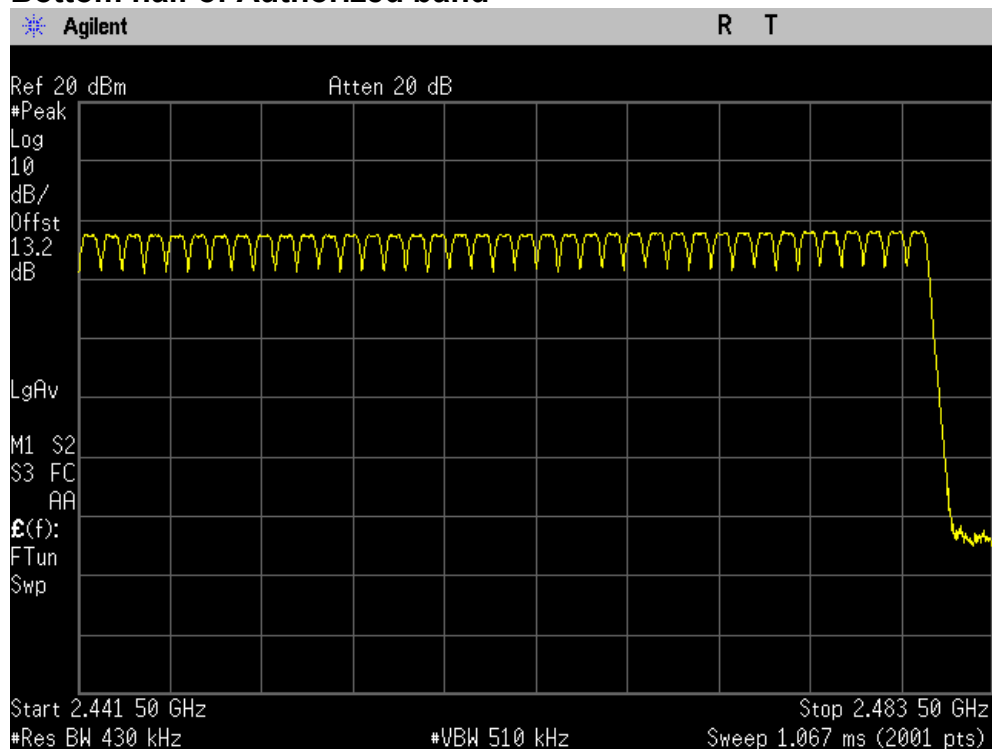
The EUT meets the specifications of Section 15.247(a)(1)(iii) for Number of Hopping Channels.

PLOT OF TEST DATA

Top half of Authorized band



Bottom half of Authorized band



TEST DATA

8.6 Peak Power Output

FCC §15.247(b)(1), RSS-210 A8.4(2)

Test mode : Set to Lowest channel, Middle channel and Highest channel

Result:

Modulation Mode	Frequency (MHz)	Peak Power (dBm)	Limit (dBm)
GFSK	2402	-2.46	30
GFSK	2441	-2.28	30
GFSK	2480	-1.77	30

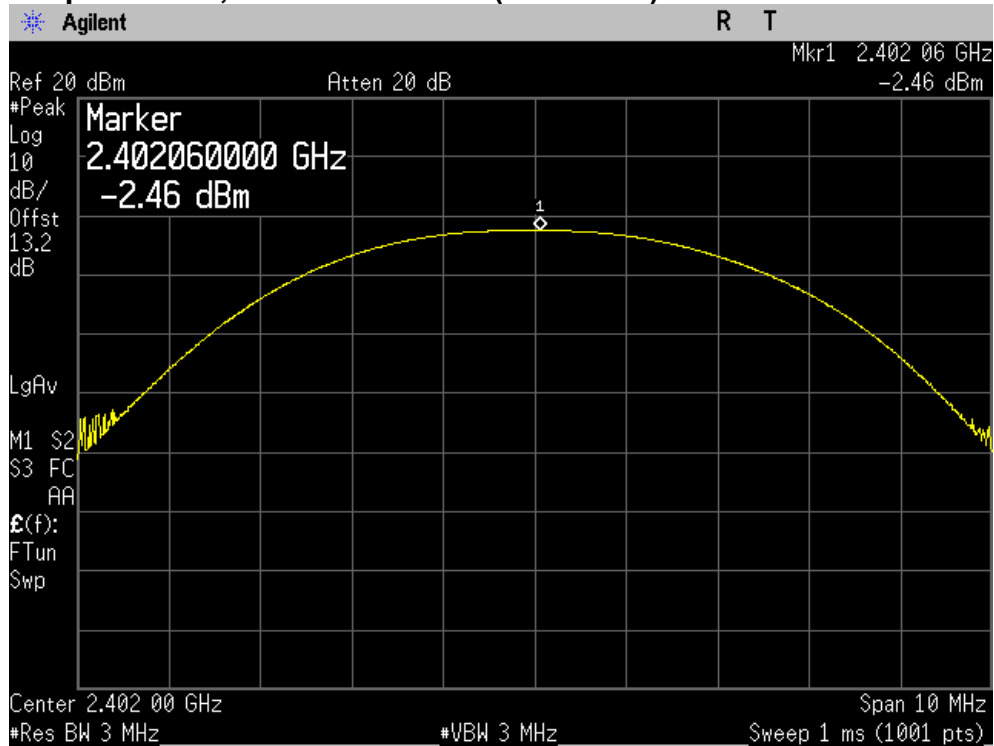
Note:

The following formular was used for spectrum offset:

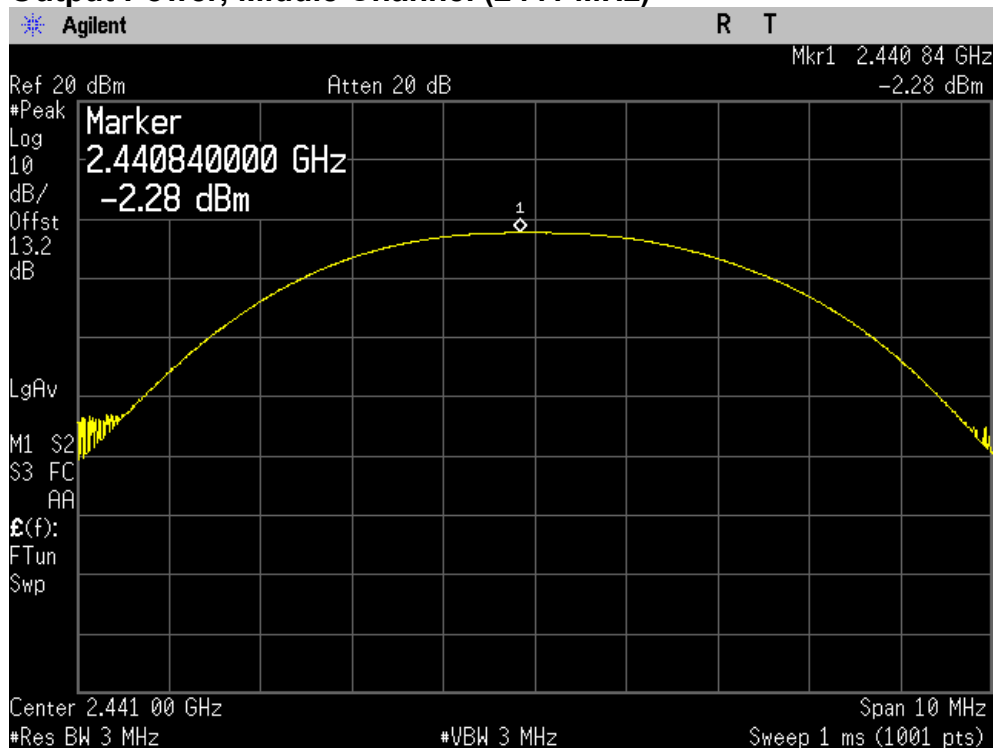
Spectrum offset (dB) = Attenuator (dB) + Cable Loss (dB) + SMA Type Connector Loss (dB)

PLOT OF TEST DATA

Output Power, Lowest Channel (2402 MHz)

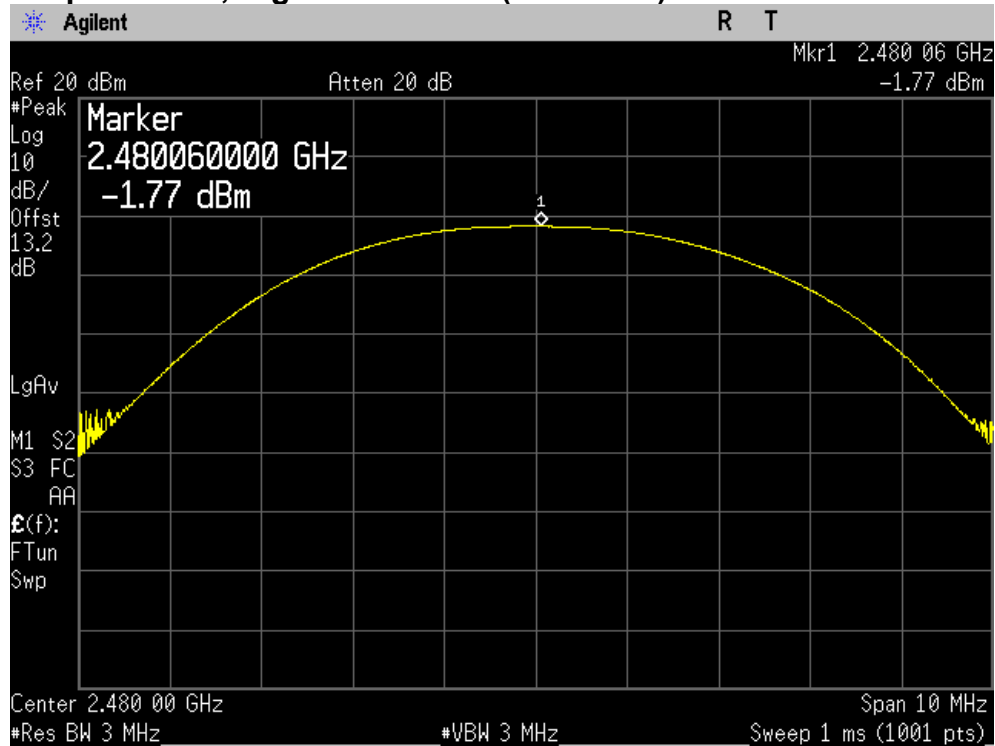


Output Power, Middle Channel (2441 MHz)



PLOT OF TEST DATA

Output Power, Highest Channel (2480 MHz)



TEST DATA

8.7 Conducted Spurious Emission

FCC §15.247(d), RSS-210 A8.5

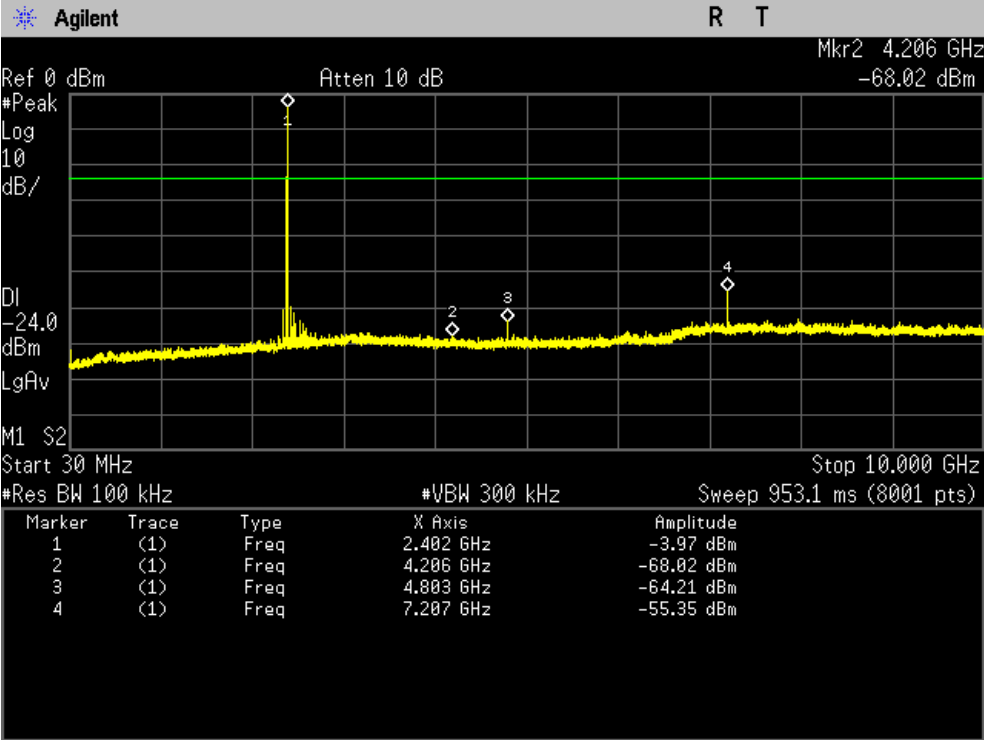
Test mode : Set to Lowest channel, Middle channel and Highest channel

Result:

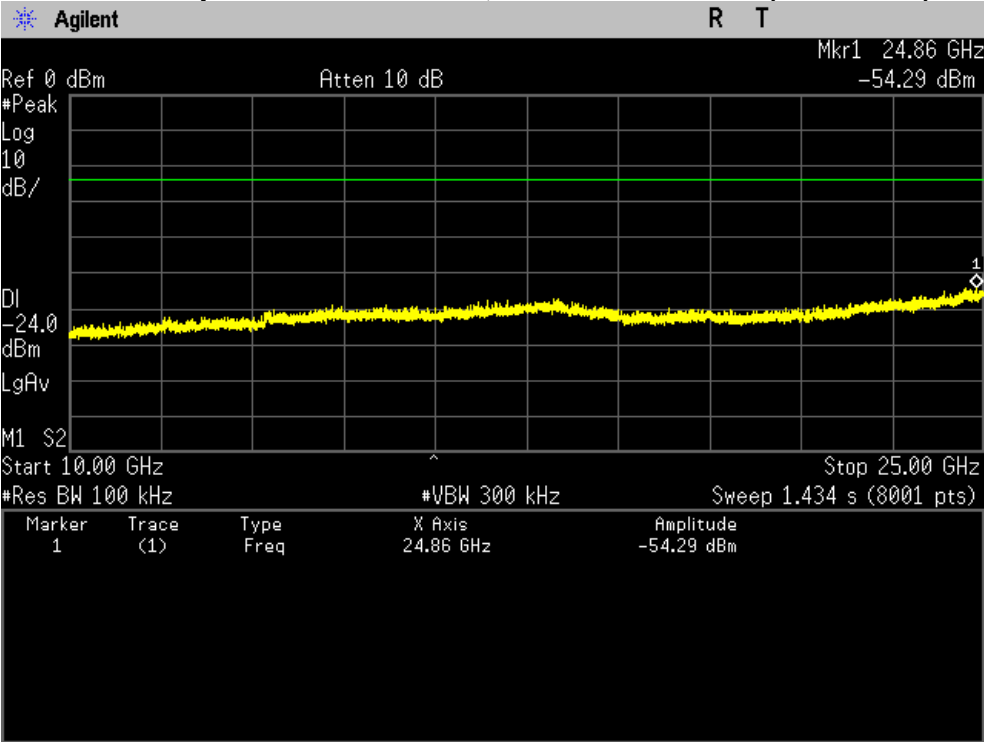
Modulation Mode	Frequency (MHz)	Spurious Emission (dBc)	Limit (dBc)
GFSK	2402	More than 30 dBc	20
GFSK	2441	More than 30 dBc	20
GFSK	2480	More than 30 dBc	20

PLOT OF TEST DATA

Conducted Spurious Emissions, 30 MHz ~ 10 GHz (2402 MHz)

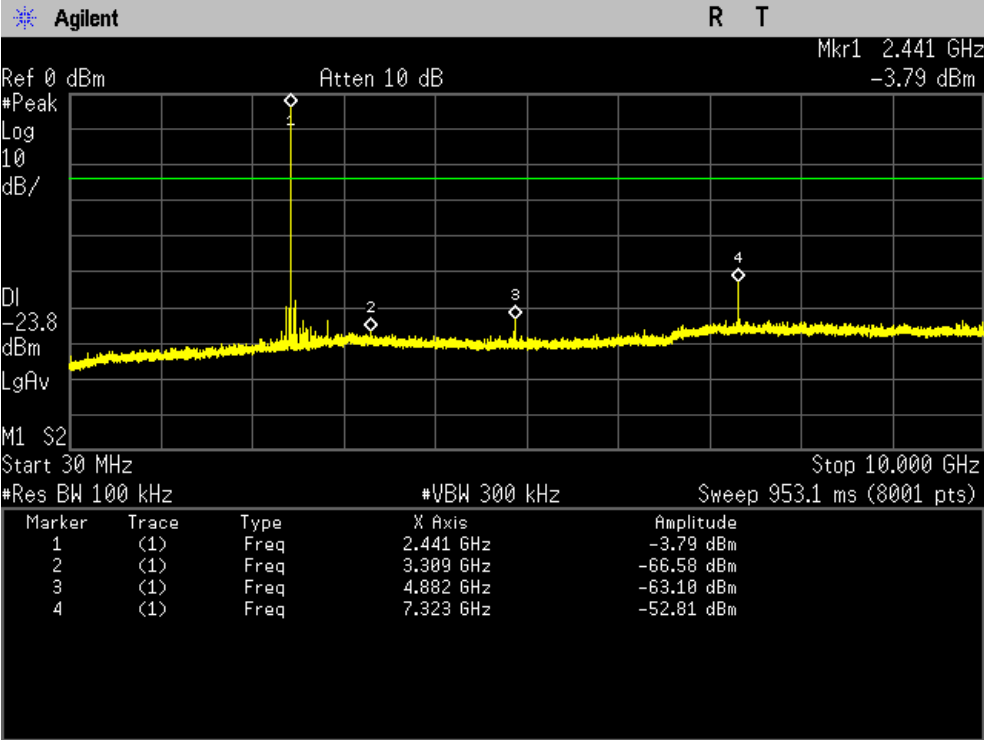


Conducted Spurious Emissions, 10 GHz ~ 26 GHz (2402 MHz)

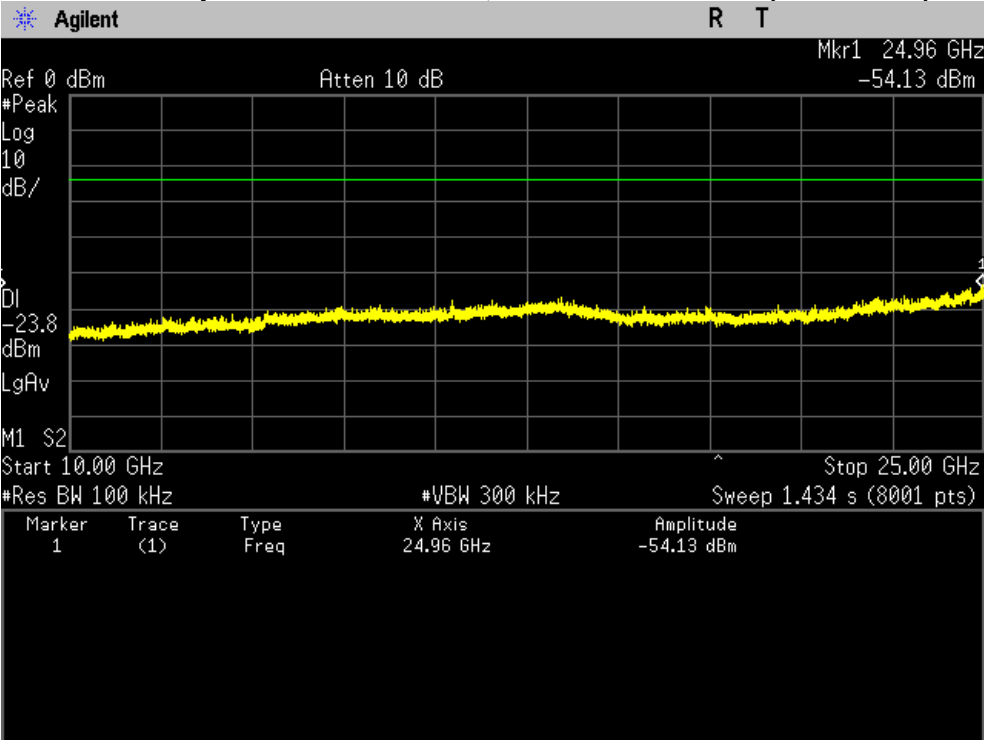


PLOT OF TEST DATA

Conducted Spurious Emissions, 30 MHz ~ 10 GHz (2441 MHz)

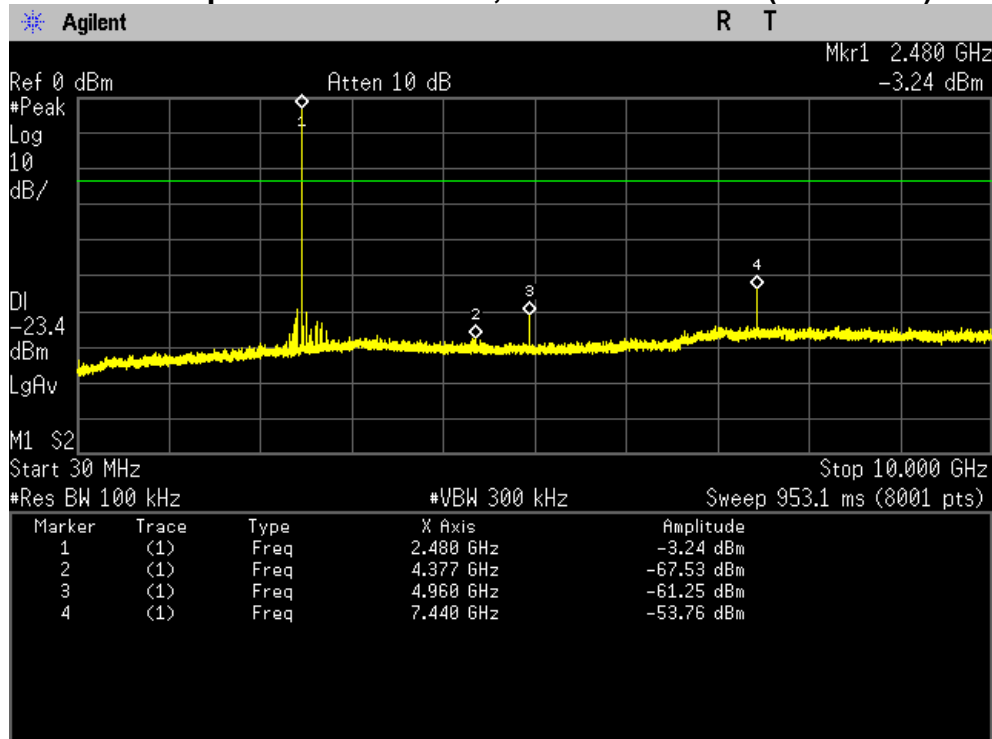


Conducted Spurious Emissions, 10 GHz ~ 26 GHz (2441 MHz)

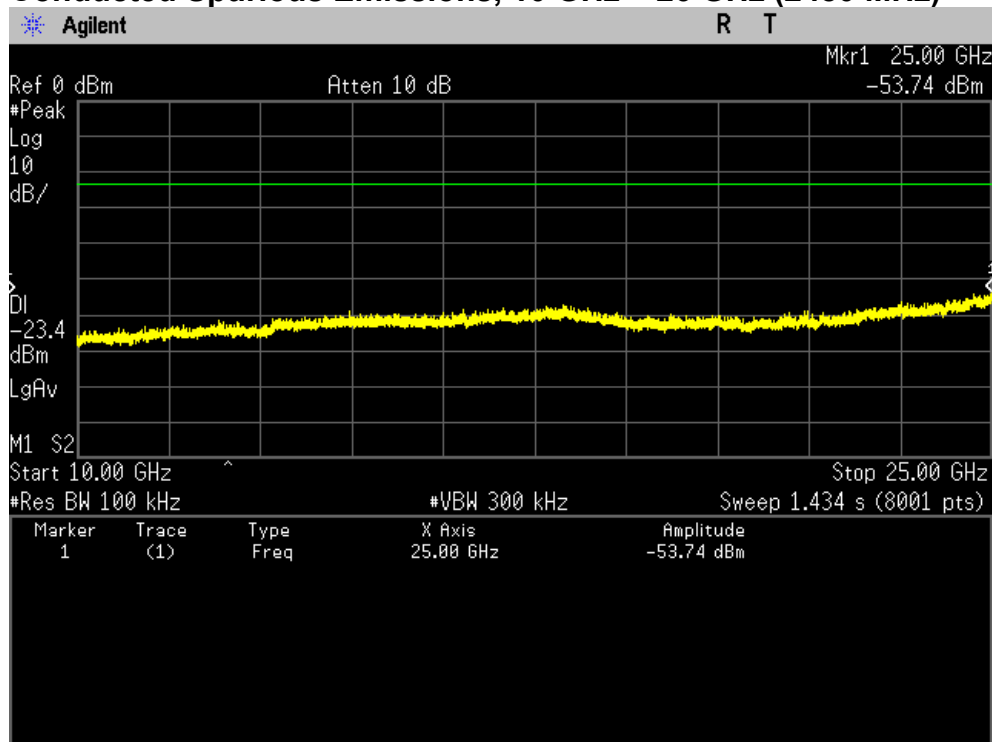


PLOT OF TEST DATA

Conducted Spurious Emissions, 30 MHz ~ 10 GHz(2480 MHz)



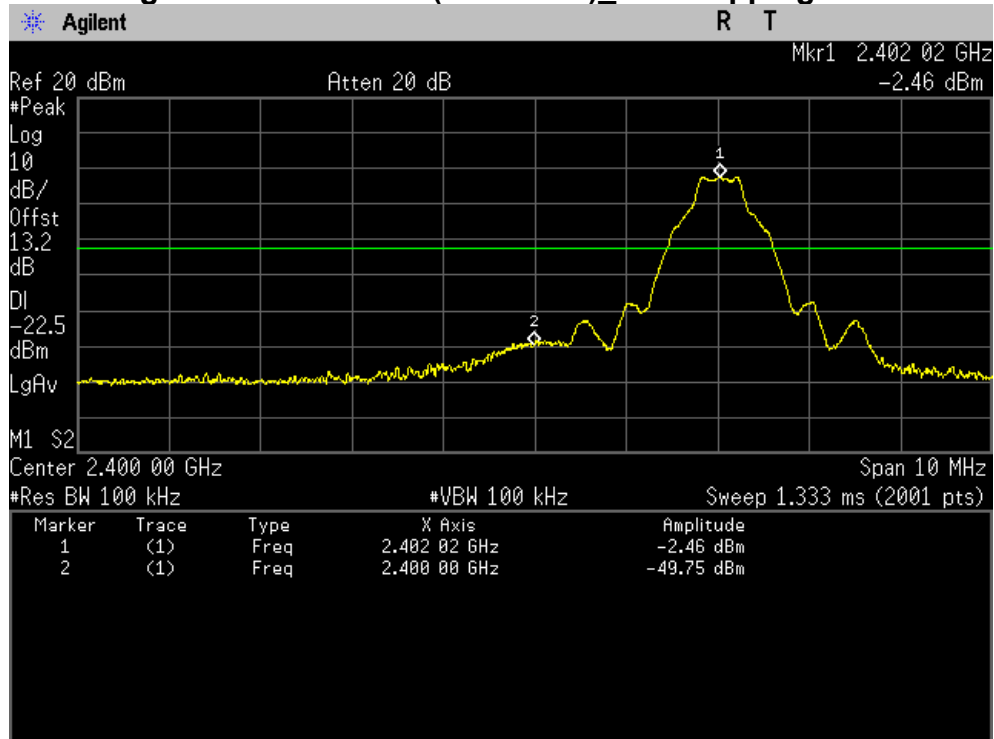
Conducted Spurious Emissions, 10 GHz ~ 26 GHz (2480 MHz)



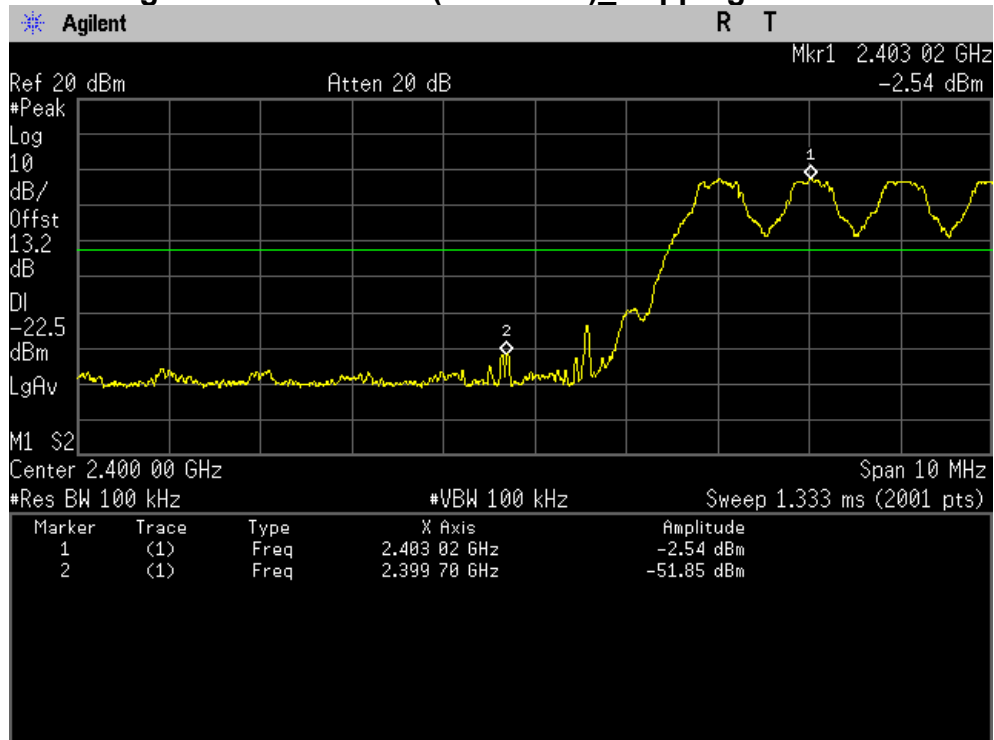
Note: The cable and attenuator loss from 30 MHz to 25 GHz was reflected in spectrum analyzer with correction factor for the Spurious emissions test.

PLOT OF TEST DATA

Band Edge Lowest Channel(2402 MHz)_Non-hopping mode

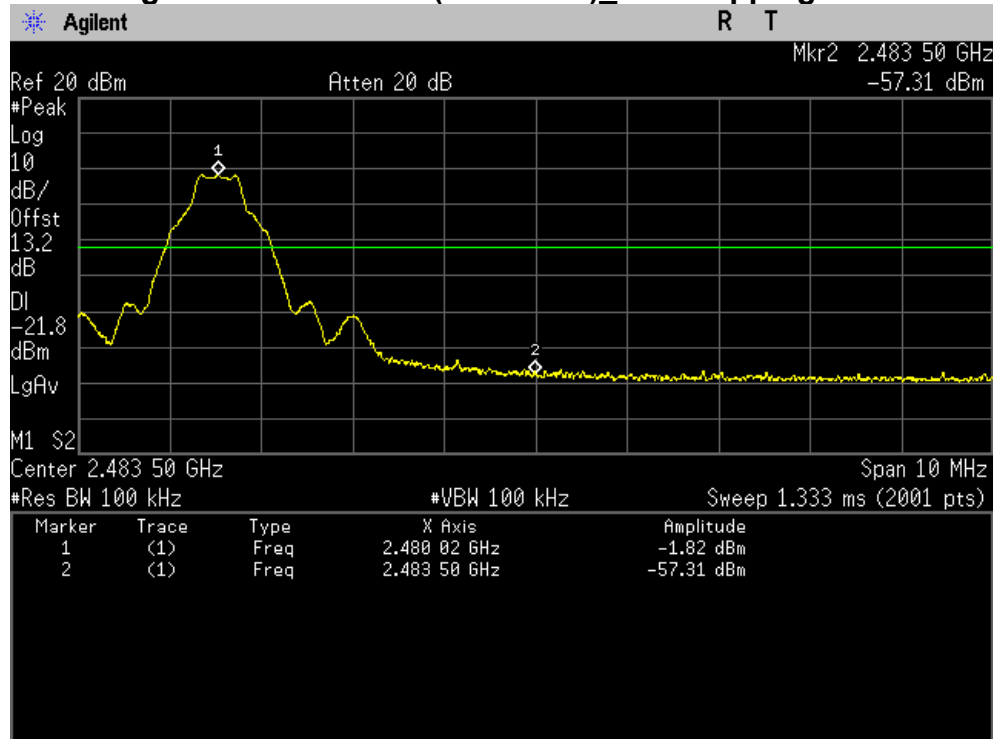


Band Edge Lowest Channel(2402 MHz)_Hopping mode

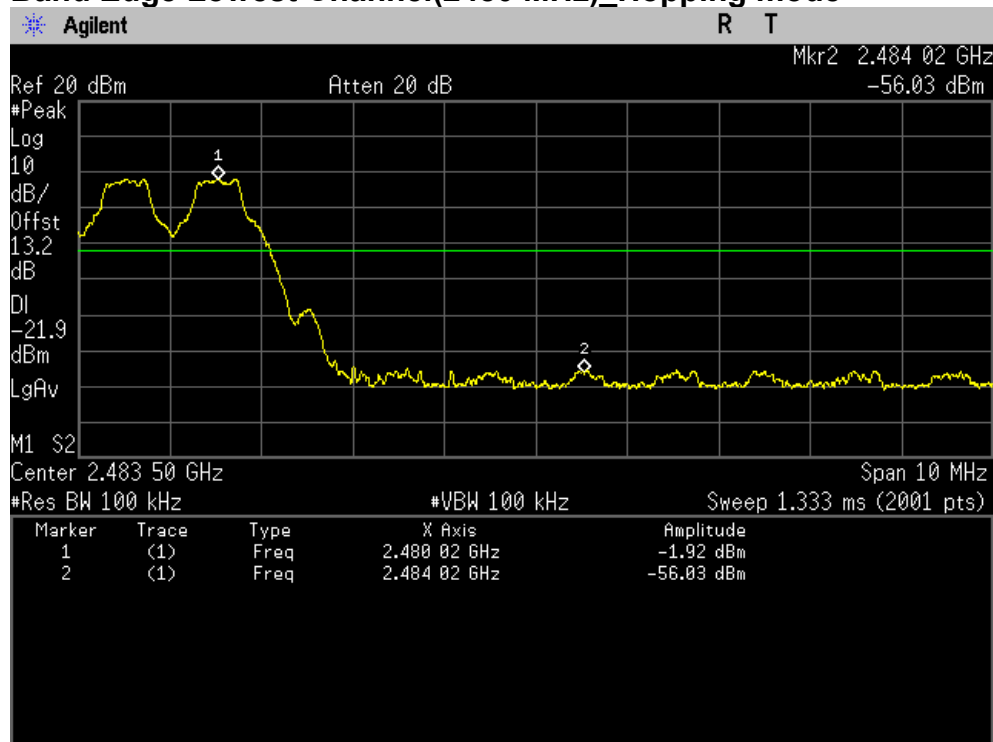


PLOT OF TEST DATA

Band Edge Lowest Channel(2480 MHz)_Non-hopping mode



Band Edge Lowest Channel(2480 MHz)_Hopping mode



TEST DATA

8.8 Radiated Spurious Emission

FCC §15.247(d), RSS-210 A8.5

Test mode : Set to Lowest channel, Middle channel and Highest channel

Result:

Lowest Channel

Frequency (MHz)	Reading (dBμV)	Pol* (H/V)	mode	AF+CL+Amp (dB)**	Result (dBμV/m)	Limit (dBμV/m)	Margin (dB)
1166.50	48.7	V	peak	-4.4	44.3	74.0	29.7
1166.50	40.3	V	average	-4.4	35.9	54.0	18.1
1333.00	47.6	H	peak	-3.8	43.8	74.0	30.2
1333.00	38.4	H	average	-3.8	34.6	54.0	19.4
1495.25	48.9	V	peak	-3.5	45.4	74.0	28.6
1495.25	39.3	V	average	-3.5	35.8	54.0	18.2
1537.00	49.1	H	peak	-3.4	45.7	74.0	28.3
1537.00	45.3	H	average	-3.4	41.9	54.0	12.1
1665.00	46.5	V	peak	-2.9	43.6	74.0	30.4
1665.00	37.7	V	average	-2.9	34.8	54.0	19.2
4804.00	39.6	V	peak	9.0	48.6	74.0	25.4
4804.00	30.3	V	average	9.0	39.3	54.0	14.7

TEST DATA

Middle Channel

Frequency (MHz)	Reading (dBμV)	Pol* (H/V)	mode	AF+CL+Amp (dB)**	Result (dBμV/m)	Limit (dBμV/m)	Margin (dB)
1104.50	46.7	H	peak	-4.6	42.1	74.0	31.9
1104.50	38.5	H	average	-4.6	33.9	54.0	20.1
1496.75	48.0	V	peak	-3.5	44.5	74.0	29.5
1496.75	38.8	V	average	-3.5	35.3	54.0	18.7
1537.00	49.3	H	peak	-3.4	45.9	74.0	28.1
1537.00	45.7	H	average	-3.4	42.3	54.0	11.7
1665.75	57.7	V	peak	-2.9	54.8	74.0	19.2
1665.75	43.8	V	average	-2.9	40.9	54.0	13.1
2246.50	47.6	V	peak	-1.3	46.3	74.0	27.7
2246.50	39.5	V	average	-1.3	38.2	54.0	15.8
4882.00	39.7	V	peak	9.2	48.9	74.0	25.1
4882.00	30.2	V	average	9.2	39.4	54.0	14.6

TEST DATA

Highest Channel

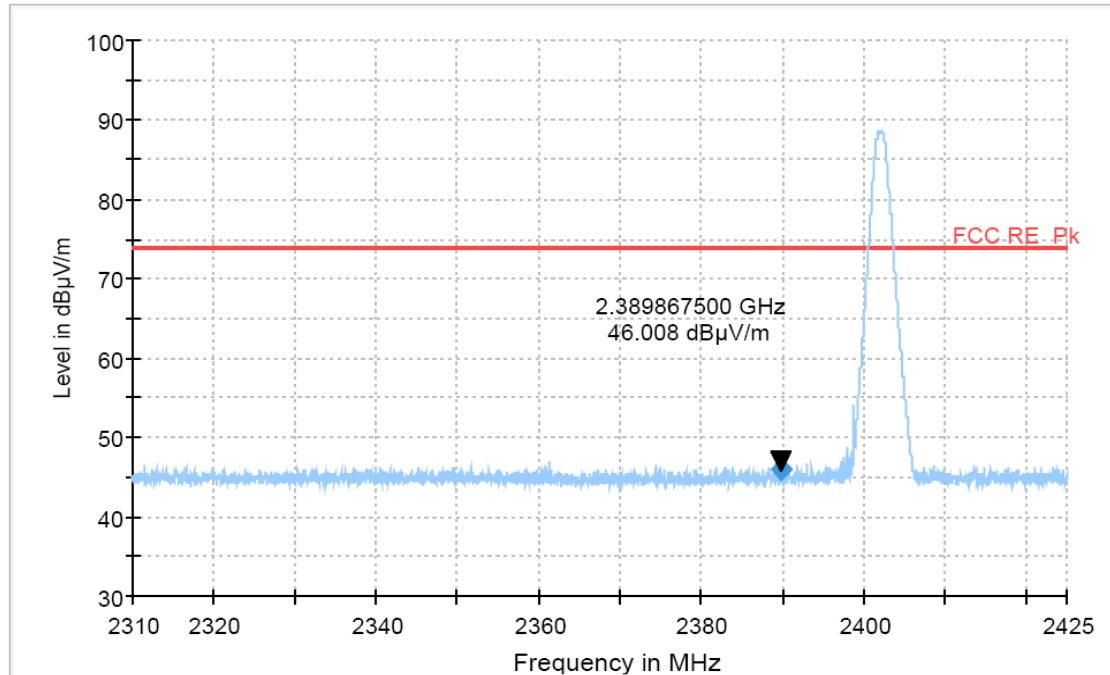
Frequency (MHz)	Reading (dBμV)	Pol* (H/V)	mode	AF+CL+Amp (dB)**	Result (dBμV/m)	Limit (dBμV/m)	Margin (dB)
1103.25	47.2	H	peak	-4.6	42.6	74.0	31.4
1103.25	38.1	H	average	-4.6	33.5	54.0	20.5
1331.00	47.4	H	peak	-3.8	43.6	74.0	30.4
1331.00	38.4	H	average	-3.8	34.6	54.0	19.4
1497.50	47.9	V	peak	-3.5	44.4	74.0	29.6
1497.50	38.4	V	average	-3.5	34.9	54.0	19.1
1537.00	49.1	H	peak	-3.4	45.7	74.0	28.3
1537.00	45.1	H	average	-3.4	41.7	54.0	12.3
1661.75	46.3	V	peak	-2.9	43.4	74.0	30.6
1661.75	37.2	V	average	-2.9	34.3	54.0	19.7
2244.50	49.1	V	peak	-1.3	47.8	74.0	26.2
2244.50	39.1	V	average	-1.3	37.8	54.0	16.2

Note:

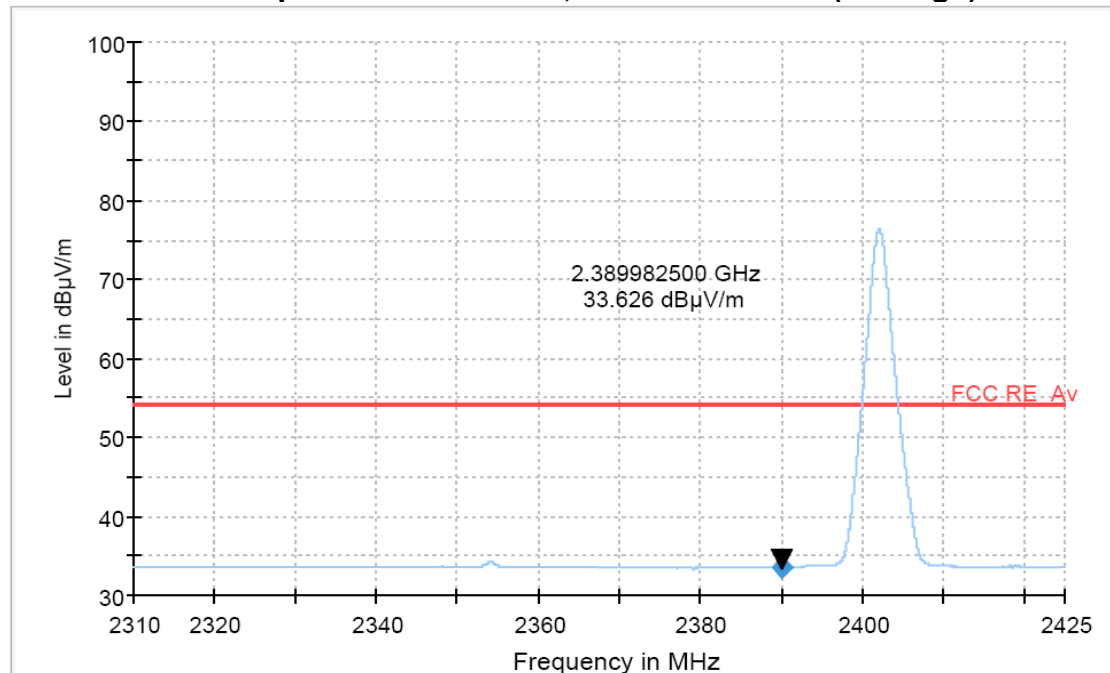
- *Pol.** H = Horizontal V = Vertical
- **AF + CL + Amp.** = Antenna Factor + Cable Loss + Amplifier.
- Other spurious** are under 20 dB below Fundamental.
- The radiated emissions testing were made by rotating through three orthogonal axes.
The worst date was recorded.
- For measurements the resolution bandwidth is set to 1 MHz, and then the video bandwidth is set to 1 MHz for peak measurements and 10 Hz for average measurements.
- The spectrum is measured from 9 kHz to 10th harmonic and the worst-case emissions are reported. No significant emissions were found beyond the fifth harmonic for this device.

PLOT OF TEST DATA

Restricted Band Spurious Emissions, Lowest channel (Peak)

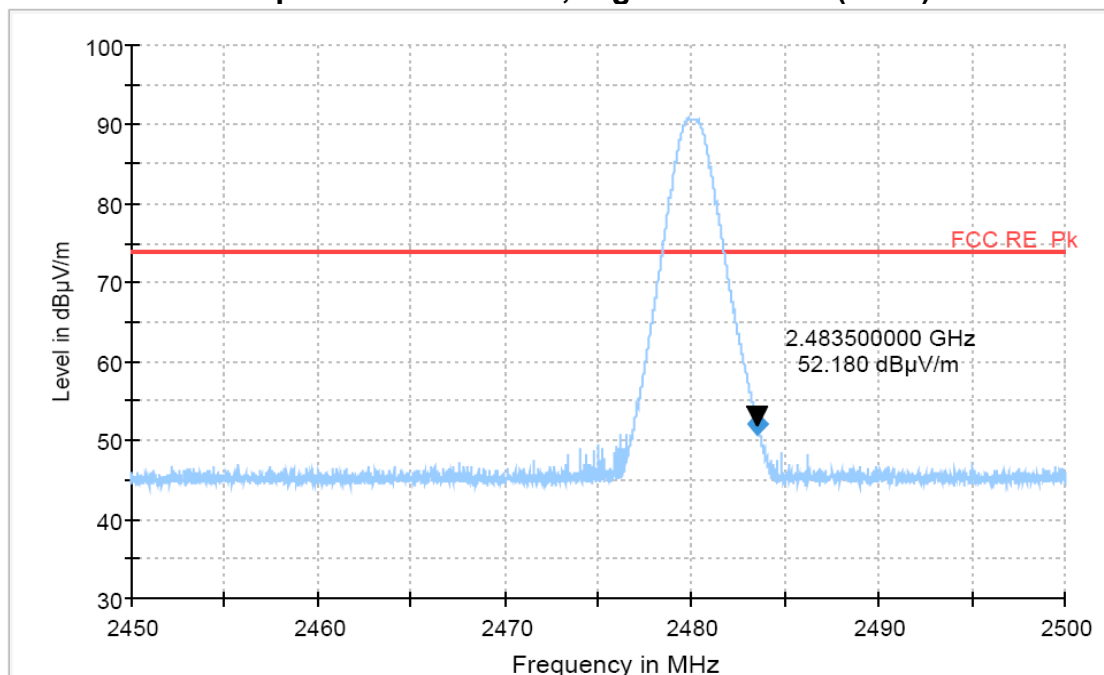


Restricted Band Spurious Emissions, Lowest channel (Average)

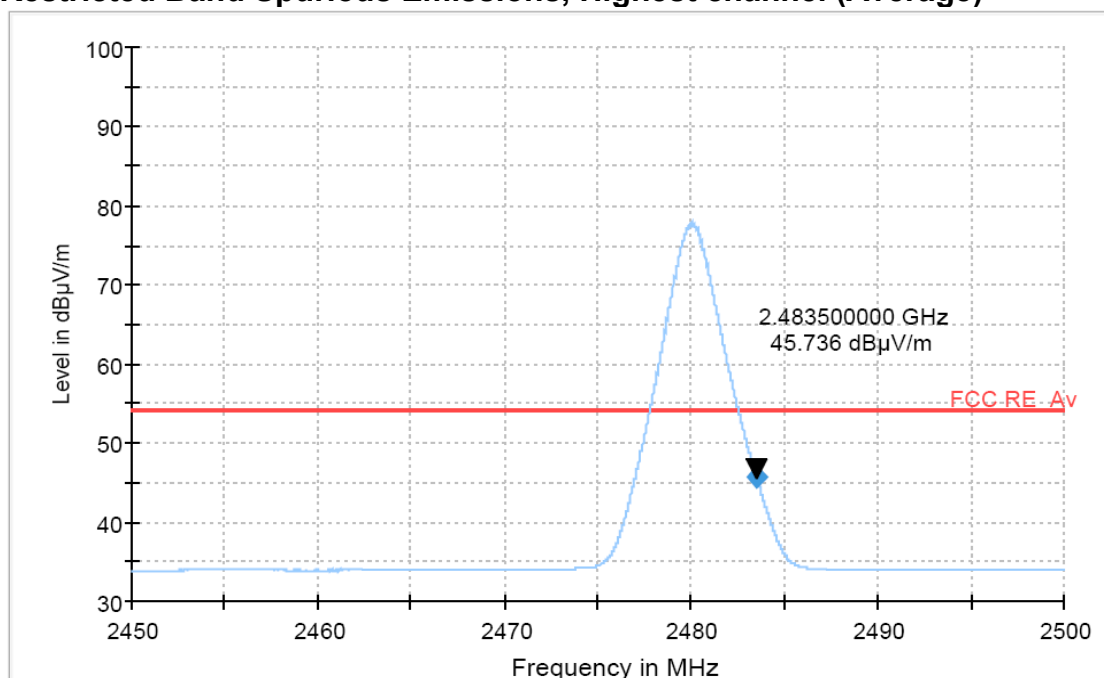


PLOT OF TEST DATA

Restricted Band Spurious Emissions, Highest channel (Peak)



Restricted Band Spurious Emissions, Highest channel (Average)



Note: For the radiated emission field strength measurements at the band edges, the resolution bandwidth was set to 1 MHz, and then the video bandwidth was set to 1 MHz for peak measurements and 10 Hz for average measurements.

9. TEST EQUIPMENT

No.	Instrument	Manufacturer	Model	Serial No.	Calibration Date	Calibration Interval
1	*Amplifier	R & S	SCU18	10065	Apr. 05 2012	1 year
2	*Amplifier	R & S	SCU26	10011	Jun. 01 2012	1 year
3	Amplifier	R & S	SCU40	10008	Jun. 01 2012	1 year
4	*Pre Amplifier	HP	8449B	3008A00107	Jan. 13 2012	1 year
5	*Spectrum Analyzer	Agilent	E4440A	MY44303257	Jul. 16 2012	1 year
6	*Spectrum Analyzer	R & S	FSP40	100361	Jul. 17 2012	1 year
7	*Loop Antenna	R & S	HFH2-Z2	100279	Aug. 31 2011	2 year
8	Wideband Power Sensor	R & S	NRP-Z81	100634	Apr. 05 2012	1 year
9	*Horn Antenna	SCHWARZBECK	BBHA9120D	9120D-508	Dec. 24 2010	2 year
10	*Horn Antenna	Q-par Angus	QSH20S20	8179	Mar. 28 2011	2 year
11	*Horn Antenna	Q-par Angus	QSH22K20	8180	Mar. 28 2011	2 year
12	LISN	R & S	ESH3-Z5	833874/006	Oct. 08 2012	1 year
13	LISN	R & S	ESH2-Z5	100227	Apr. 04 2012	1 year
14	*Anechoic Chamber	EM Eng.	N/A	N/A	N/A	N/A
15	*Shielded Room	EM Eng.	N/A	N/A	N/A	N/A
16	*Position Controller	innco systems GmbH	CO2000	CO2000/329/124BD406/L	N/A	N/A
17	*Turn Table	innco systems GmbH	DS1200S	N/A	N/A	N/A
18	*Antenna Mast	innco systems GmbH	MA4000	N/A	N/A	N/A
19	*Anechoic Chamber	Seo-Young EMC	N/A	N/A	N/A	N/A
20	*EMI test receiver	R & S	ESU 40	100202	Apr. 04 2012	1 year
21	*Trilog broadband test antenna	SCHWARZBECK	VULB 9163	9163-423	Jun. 09 2012	2 year
22	*Attenuator	Fairview	SA3N5W-06	N/A	Apr. 04 2012	
23	*Controller	innco systems GmbH	CO2000-G	N/A	N/A	N/A
24	*Open switch and control unit	R & S	OSP-120	100015	N/A	N/A
25	*Antenna mast	innco systems GmbH	MA4000-EP	N/A	N/A	N/A
26	*Turn table	innco systems GmbH	DT3000-3T	N/A	N/A	N/A
27	*Pre Amplifier	R & S	SCU 01	10030	Apr. 04 2012	1 year

*) Test equipment used during the test

10. ACCURACY OF MEASUREMENT

The Measurement Uncertainties stated were calculated in accordance with the requirements of measurement uncertainty contained in CISPR 16-4-2 with the confidence level of 95%

1. Conducted Uncertainty Calculation

Source of Uncertainty	X_i	Uncertainty of X_i		Coverage factor k	$u(X_i)$ (dB)	C_i	$C_i u(X_i)$ (dB)
		Value (dB)	Probability Distribution				
Receiver reading	RI	± 0.1	normal 1	1.000	0.1	1	0.1
Attenuation AMN-Receiver	LC	± 0.08	normal 2	2.000	0.04	1	0.04
AMN Voltage division factor	LAMN	± 0.8	normal 2	2.000	0.4	1	0.4
Sine wave voltage	dVSW	± 2.00	normal 2	2.000	1.00	1	1.00
Pulse amplitude response	dVPA	± 1.50	rectangular	1.732	0.87	1	0.87
Pulse repetition rate response	dVPR	± 1.50	rectangular	1.732	0.87	1	0.87
Noise floor proximity	dVNF	± 0.00	-	-	0.00	1	0.00
AMN Impedance	dZ	± 1.80	triangular	2.449	0.73	1	0.73
Ⓐ Mismatch	M	+ 0.70	U-Shaped	1.414	0.49	1	0.49
Ⓑ Mismatch	M	- 0.80	U-Shaped	1.414	- 0.56	1	- 0.56
Measurement System Repeatability	RS	0.05	normal 1	1.000	0.05	1	0.05
Remark	Ⓐ: AMN-Receiver Mismatch : + Ⓑ: AMN-Receiver Mismatch : -						
Combined Standard Uncertainty	Normal			± 1.88			
Expended Uncertainty U	Normal ($k = 2$)			± 3.76			

2. Radiation Uncertainty Calculation

Source of Uncertainty	X_i	Uncertainty of X_i		Coverage factor k	$u(X_i)$ (dB)	C_i	$C_i u(X_i)$ (dB)
		Value (dB)	Probability Distribution				
Receiver reading	RI	± 0.10	normal 1	1.000	0.10	1	0.10
Sine wave voltage	dV_{sw}	± 2.00	normal 2	2.000	1.00	1	1.00
Pulse amplitude response	dV_{pa}	± 1.50	rectangular	1.732	0.87	1	0.87
Pulse repetition rate response	dV_{pr}	± 1.50	rectangular	1.732	0.87	1	0.87
Noise floor proximity	dV_{nf}	± 0.50	normal 2	2.000	0.25	1	0.25
Antenna Factor Calibration	AF	± 1.50	normal 2	2.000	0.75	1	0.75
Attenuation Antenna-receiver	CL	± 0.52	normal 2	2.000	0.26	1	0.26
Antenna Directivity	AD	± 1.00	rectangular	1.732	0.58	1	0.58
Antenna Factor Height Dependence	AH	± 0.50	rectangular	1.732	0.29	1	0.29
Antenna Phase Centre Variation	AP	± 0.30	rectangular	1.732	0.17	1	0.17
Antenna Factor Frequency Interpolation	AI	± 0.30	rectangular	1.732	0.17	1	0.17
Site Imperfections	SI	± 4.00	triangular	2.449	1.63	1	1.63
Measurement Distance Variation	DV	± 0.10	rectangular	1.732	0.06	1	0.06
Antenna Balance	$Dbal$	± 0.90	rectangular	1.732	0.52	1	0.52
Cross Polarisation	$DCross$	± 0.90	rectangular	1.732	0.52	1	0.52
Ⓐ Mismatch	M	+ 0.25	U-Shaped	1.414	0.18	1	0.18
Ⓑ Mismatch	M	- 0.26	U-Shaped	1.414	- 0.18	1	- 0.18
Ⓒ Mismatch	M	+ 0.98	U-Shaped	1.414	0.69	1	0.69
Ⓓ Mismatch	M	- 1.11	U-Shaped	1.414	- 0.79	1	- 0.79
Measurement System Repeatability	RS	0.09	normal 1	1.000	0.09	1	0.09
Remark	Ⓐ: Biconical Antenna-receiver Mismatch : + (< 200 MHz) Ⓑ: Biconical Antenna-receiver Mismatch : - (< 200 MHz) Ⓒ: Log Periodic Antenna-receiver Mismatch : + ($\geq$ 200 MHz) Ⓓ: Log Periodic Antenna-receiver Mismatch : - ($\geq$ 200 MHz)						
Combined Standard Uncertainty	Normal			± 2.63 (< 200 MHz) ± 2.74 ($\geq$ 200 MHz)			
Expanded Uncertainty U	Normal ($k = 2$)			± 5.26 (< 200 MHz) ± 5.48 ($\geq$ 200 MHz)			